

The Future of Devices & Chips: A Blast from the Past?

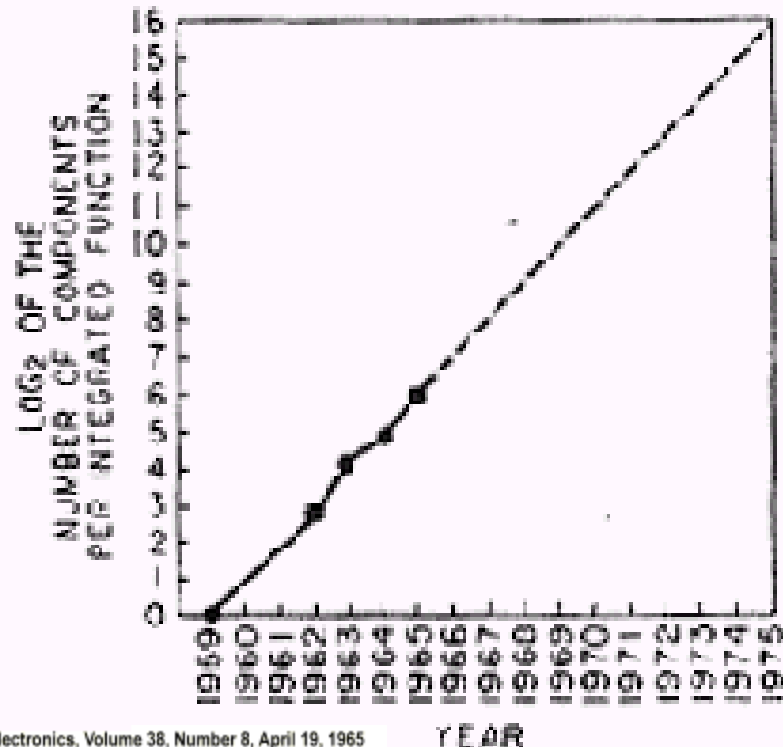
Elad Alon

**Collaborators: Tsu-Jae King Liu (UC Berkeley),
Dejan Markovic (UCLA), Vladimir Stojanovic (MIT)**



**Berkeley Wireless Research Center
University of California, Berkeley**

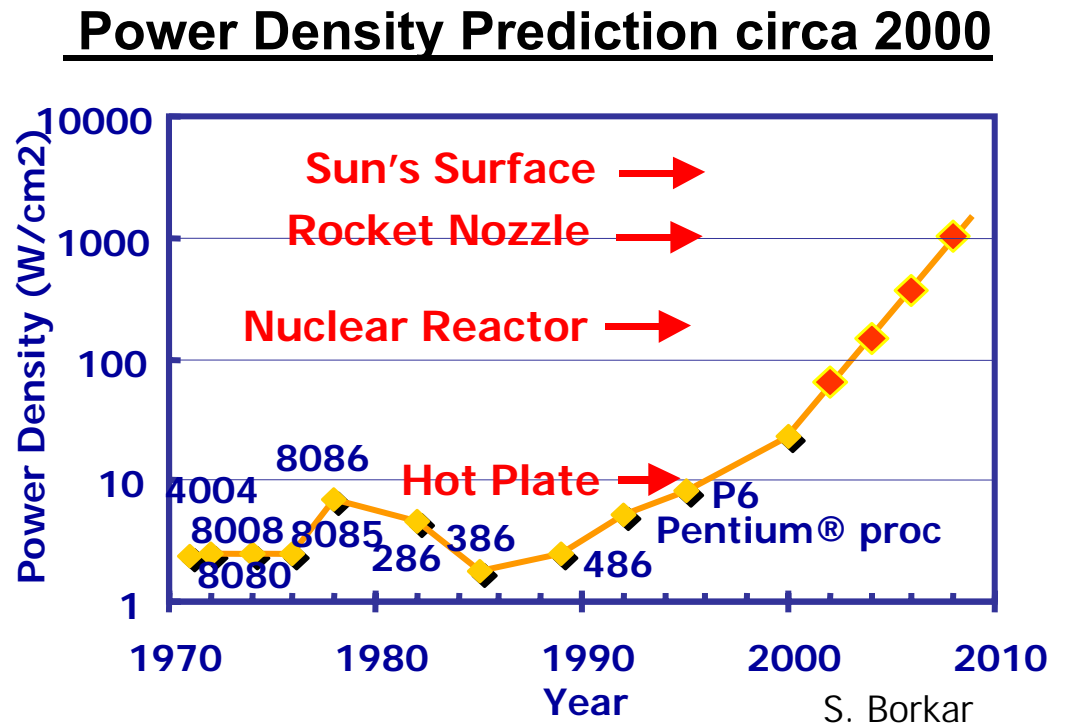
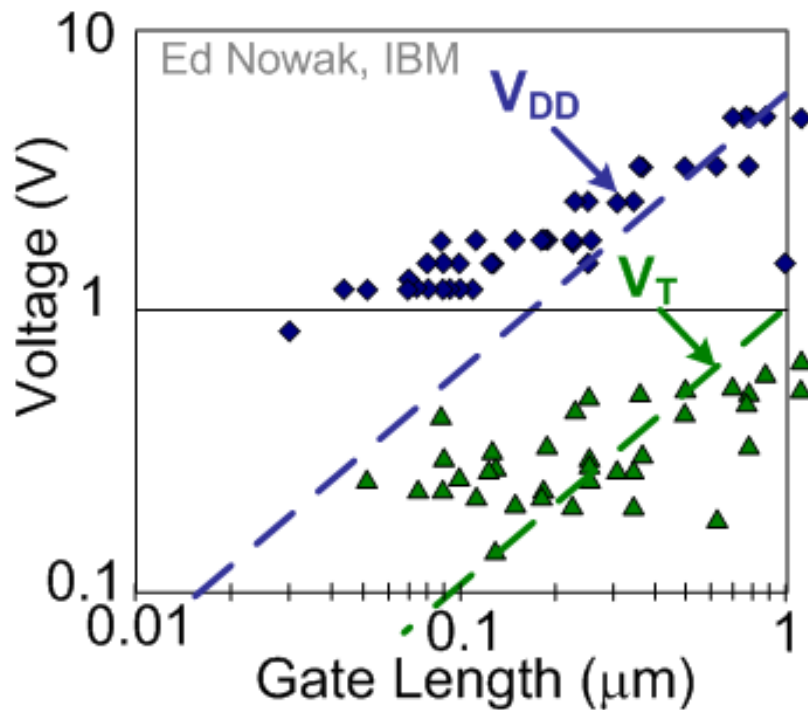
Moore's Law and Original Issues



- ❑ Design cost
- ❑ What to do with all of the functionality possible
- ❑ Power dissipation

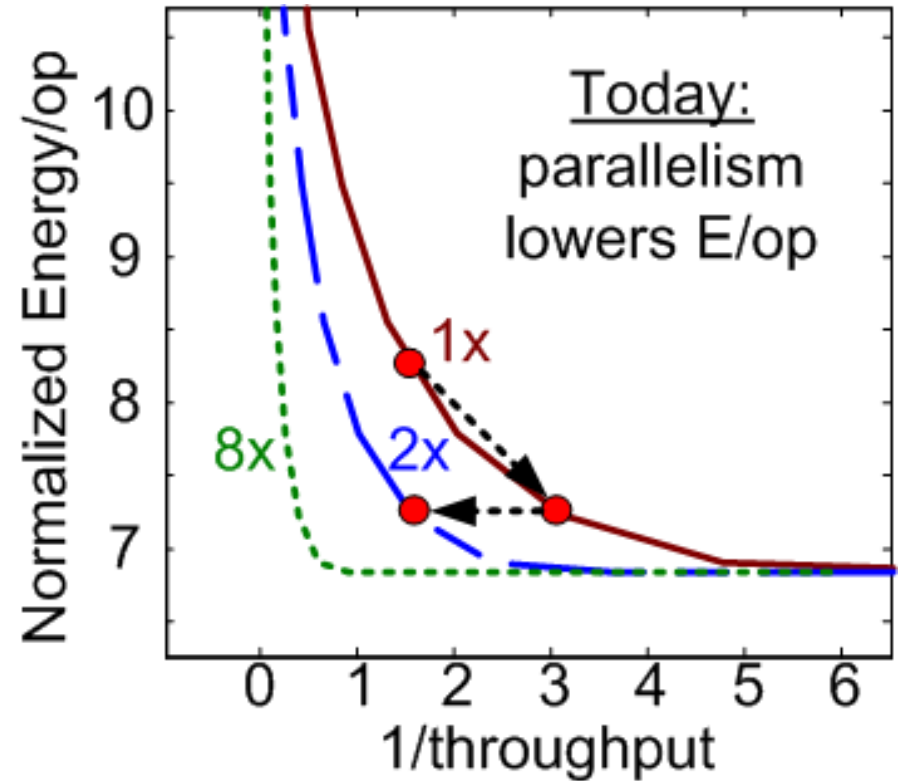
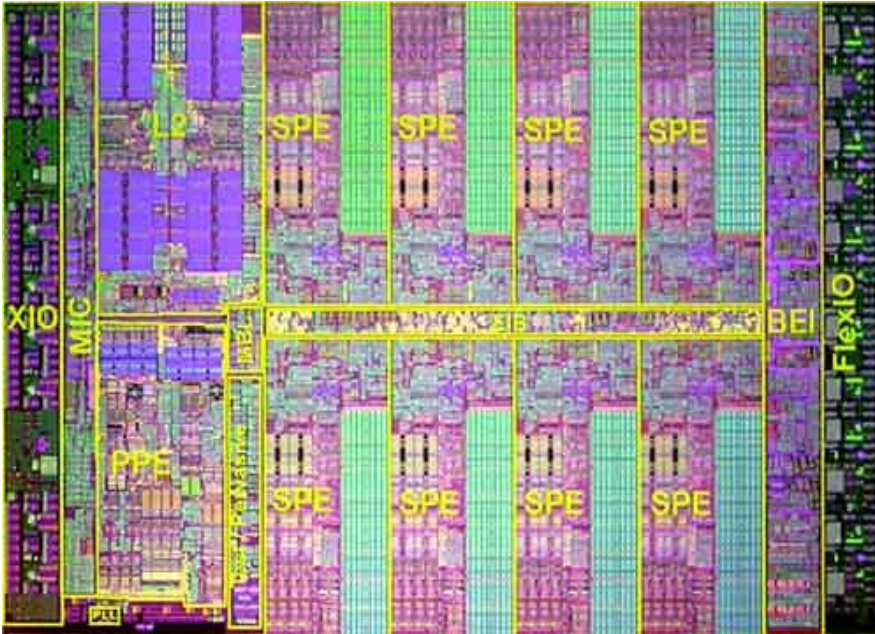


Power Consumption...



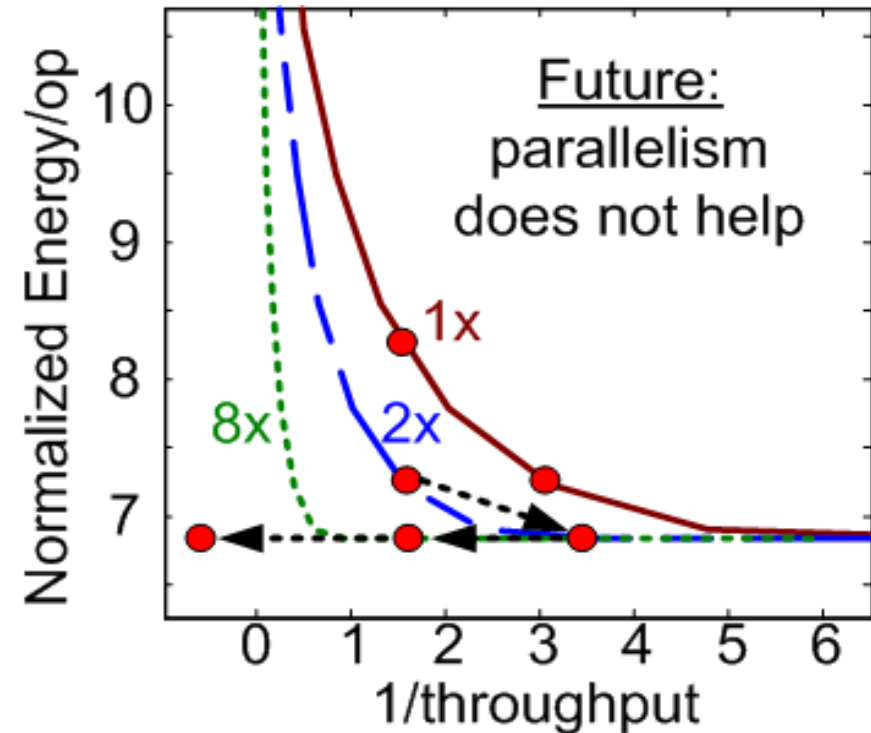
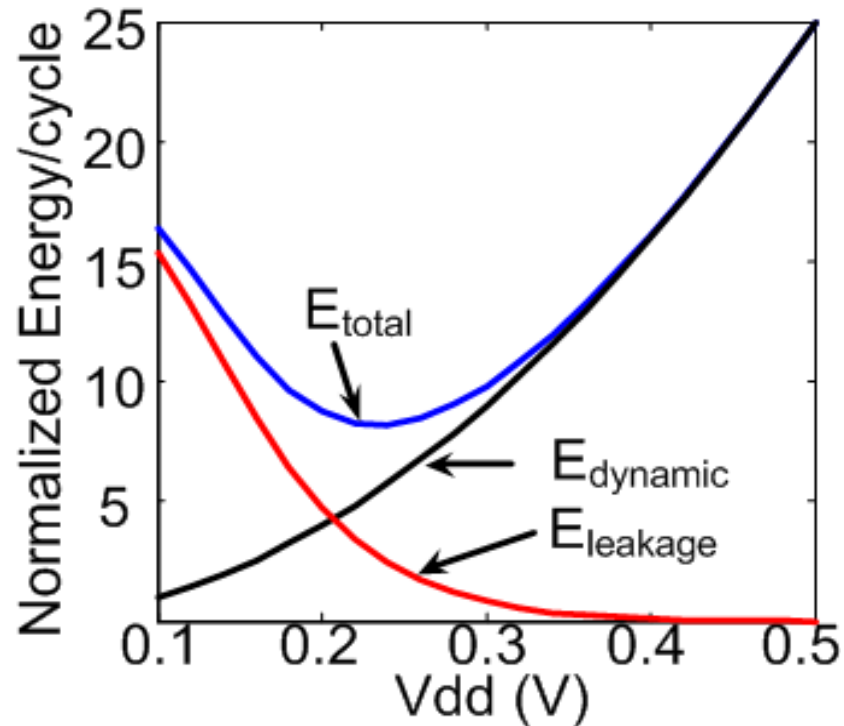
- ❑ Since ~2000 supply voltage (V_{dd}) stuck at ~1V
 - Leakage stops you from lowering threshold (V_{th})
- ❑ Leads to very poor power scaling
 - 1kW chips?

Parallelism to the Rescue



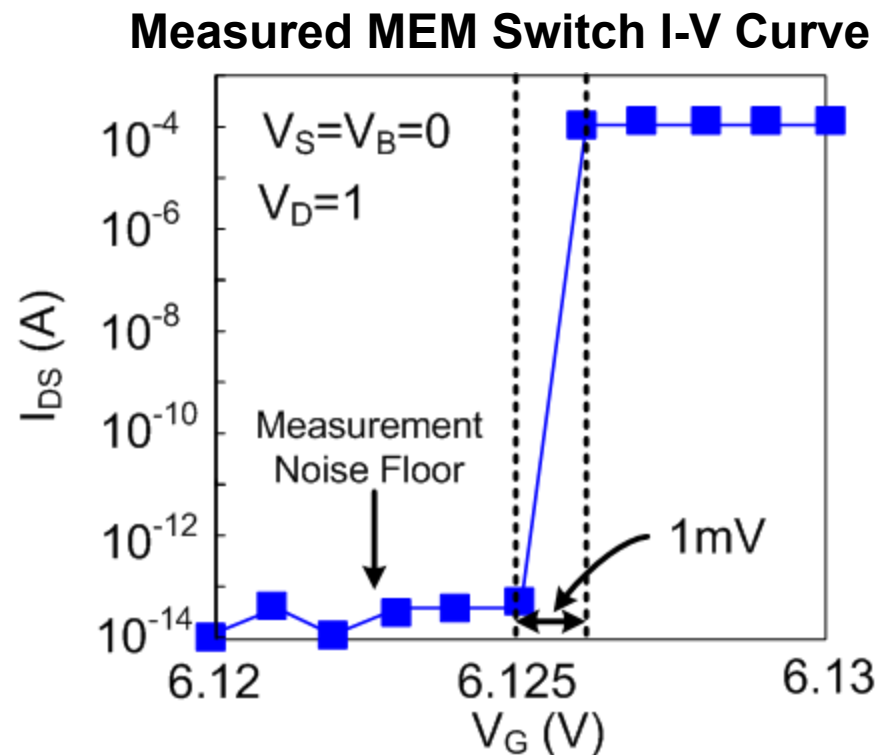
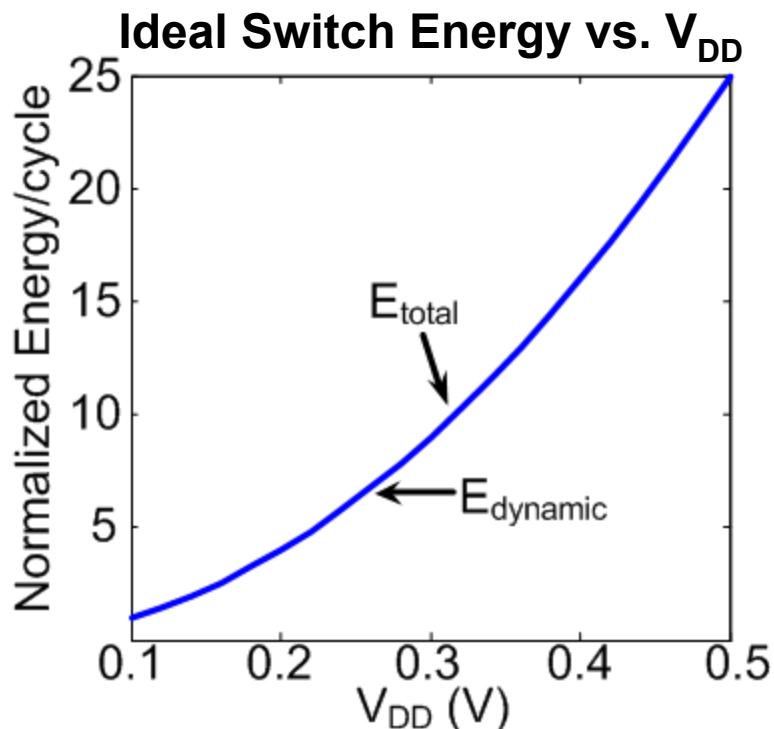
- ❑ Parallelism allows slower, more energy-efficient units while maintaining performance
- ❑ Will this last forever?

Where Parallelism Doesn't Help



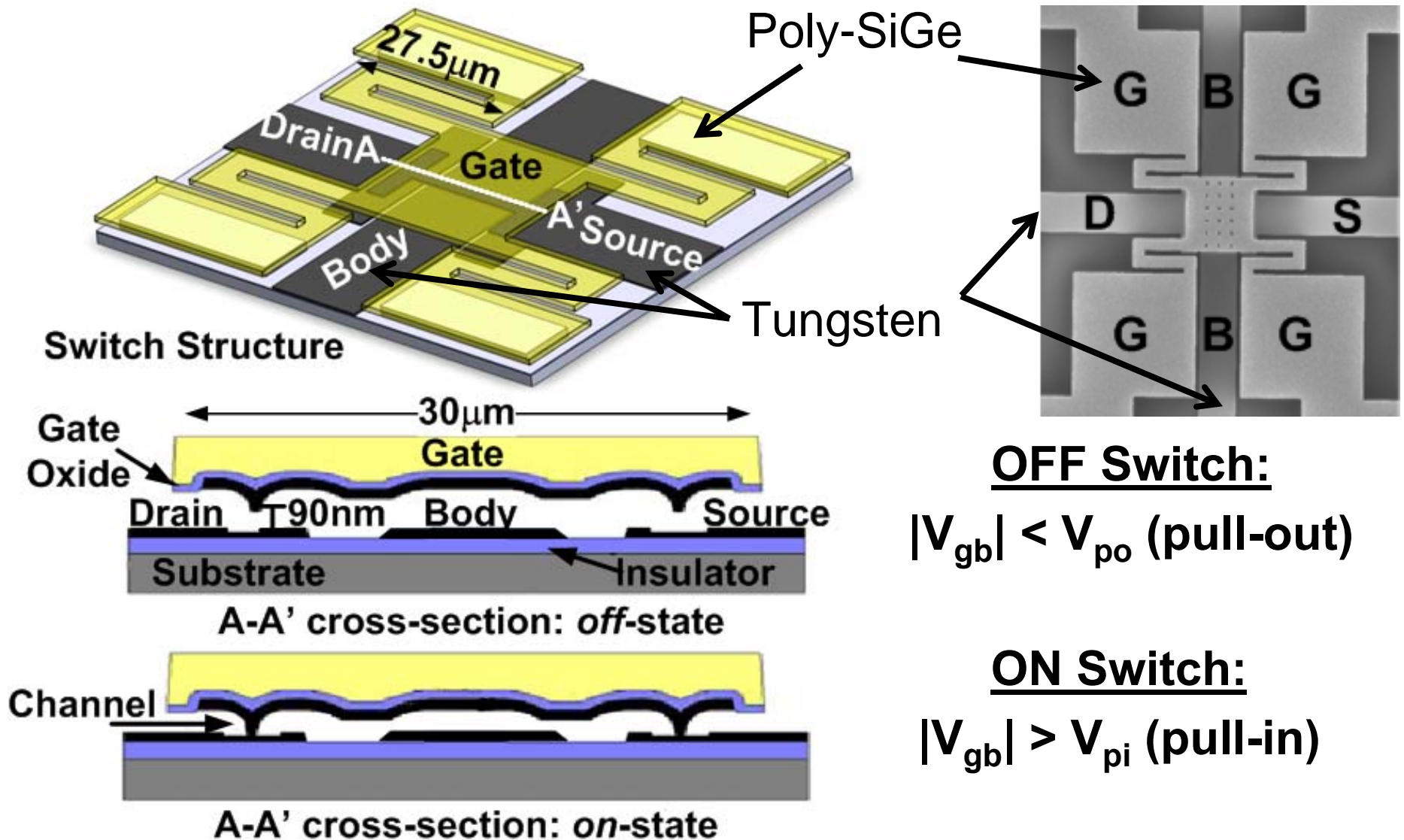
- ❑ CMOS circuits have an absolute minimum energy/op
 - Need to balance leakage and active energies
- ❑ Limits energy-efficiency, no matter how slowly the circuit runs

What if There Was No Leakage?

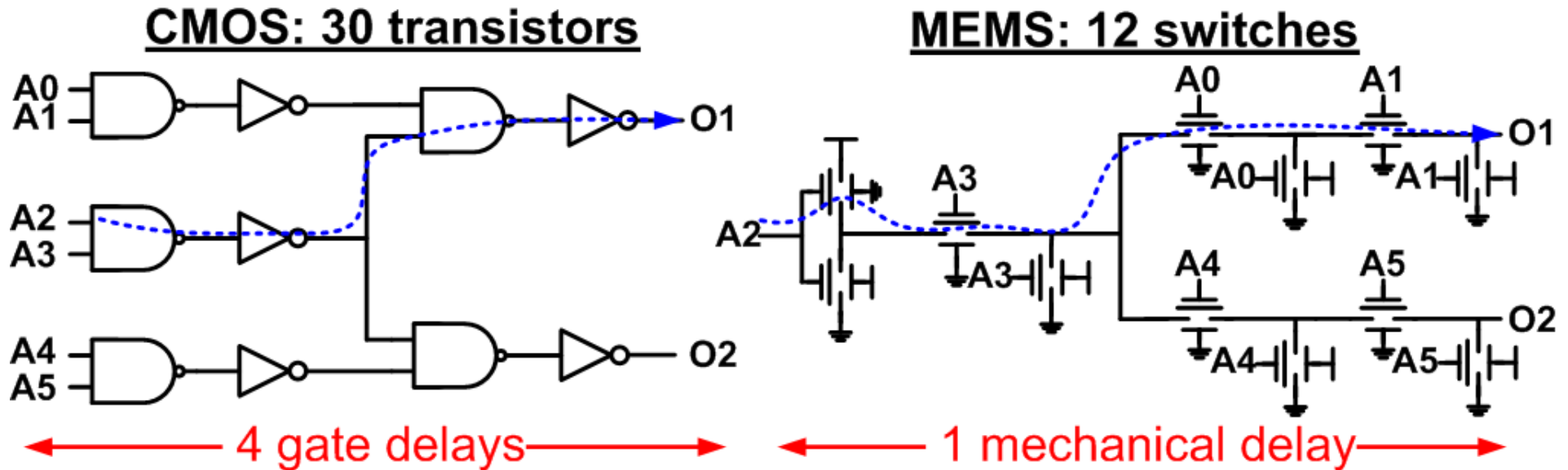


- ❑ Supply voltage decreases → energy decreases
- ❑ Mechanical switches don't leak, turn on abruptly
 - Potential pathway to continued scaling

Switch Structure & Operation

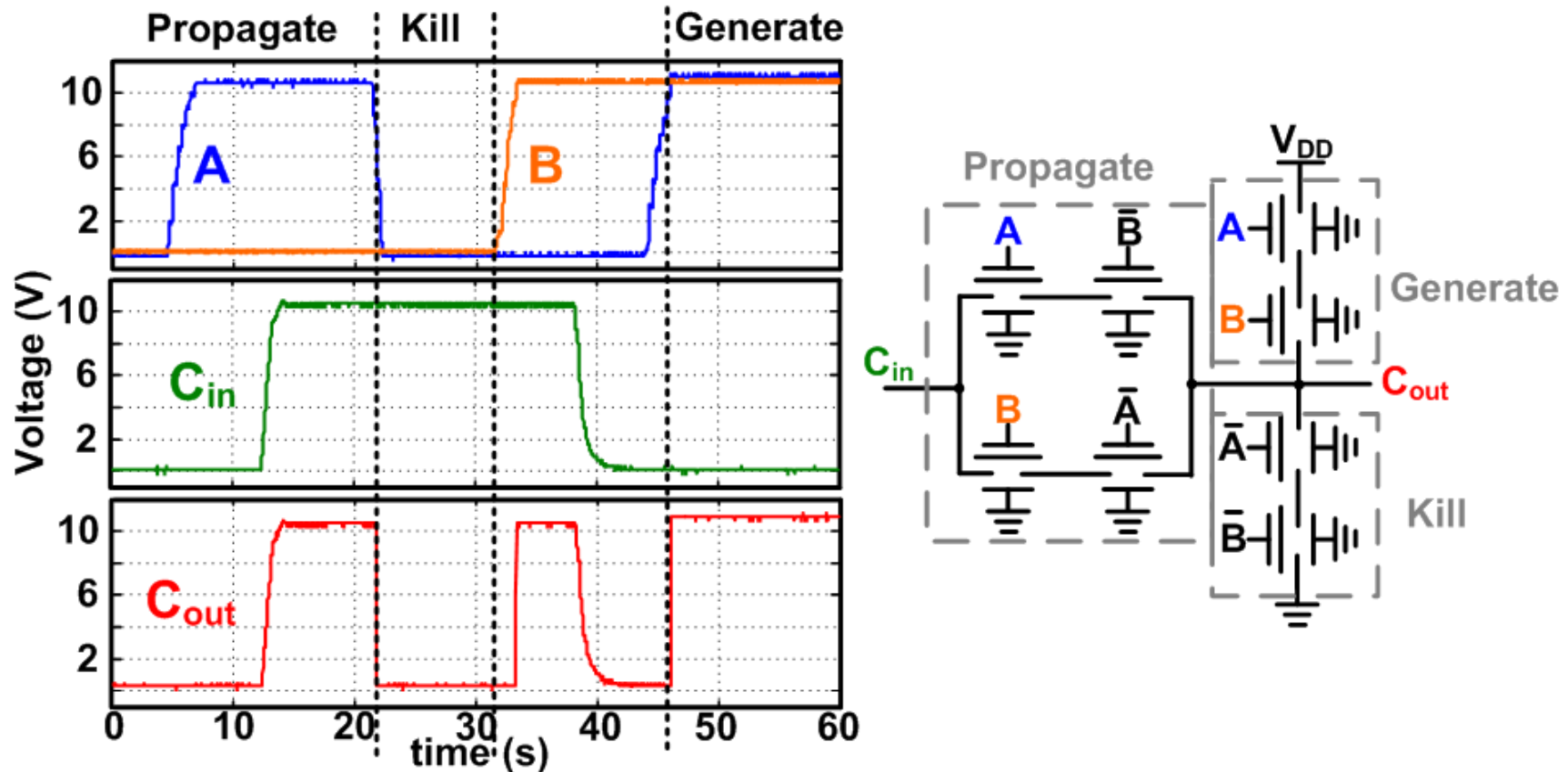


Relay Logic



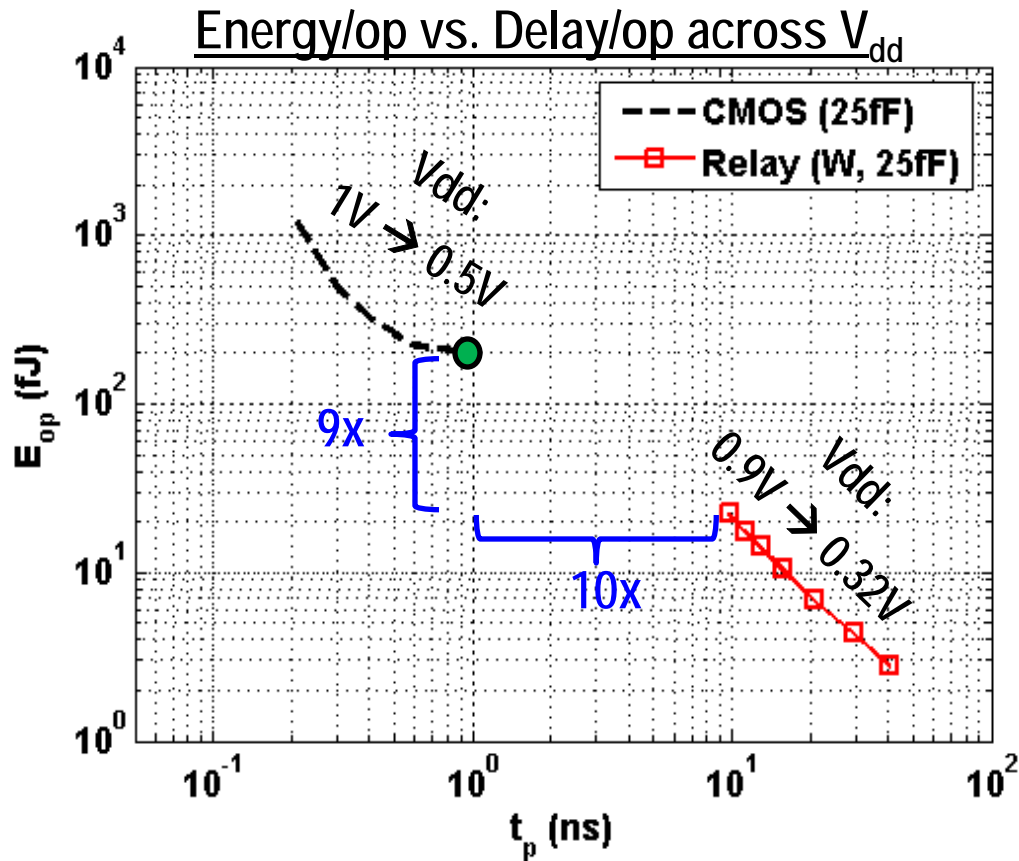
- ❑ Relay delay dominated by mechanical motion
- ❑ So, implement logic as a single complex gate
 - All devices move at the same time
- ❑ Improves area, device count, performance

Logic Demonstration



- ❑ Relays built with 1 μ m lithography - clearly not yet competitive with CMOS...
 - What does it take to get there?

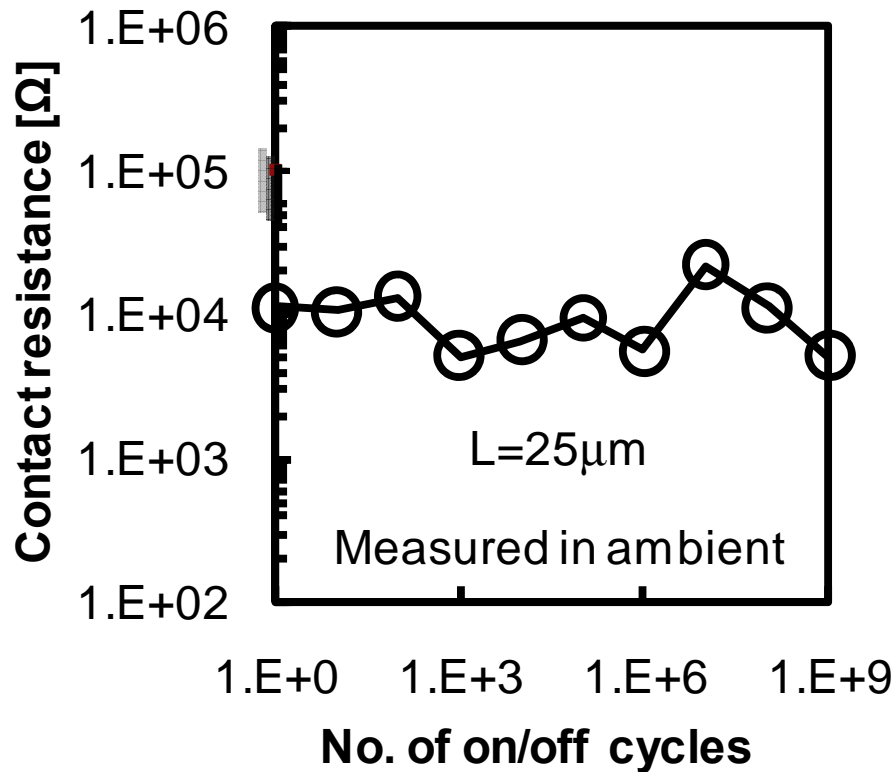
Scaling and Comparing to CMOS



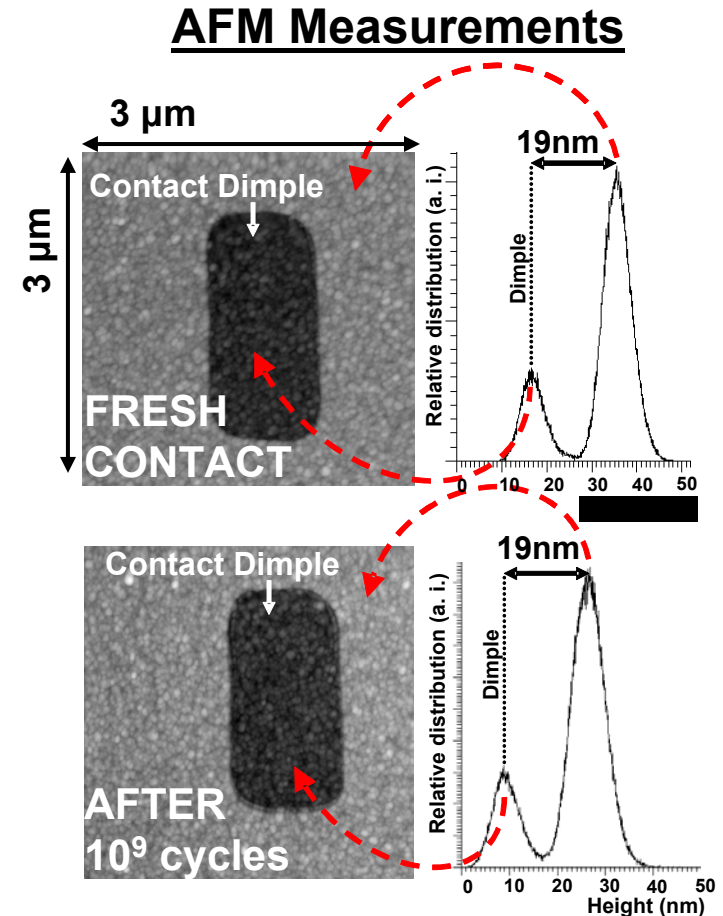
- Scaling similar to CMOS
 - Smaller = faster, lower voltage, lower power
- At 90nm, simulated relay adders are:
 - >9x lower E/op
 - >10x greater delay

- Reminder: parallelism enables high throughput
 - Even with slower individual elements

Relay Reliability

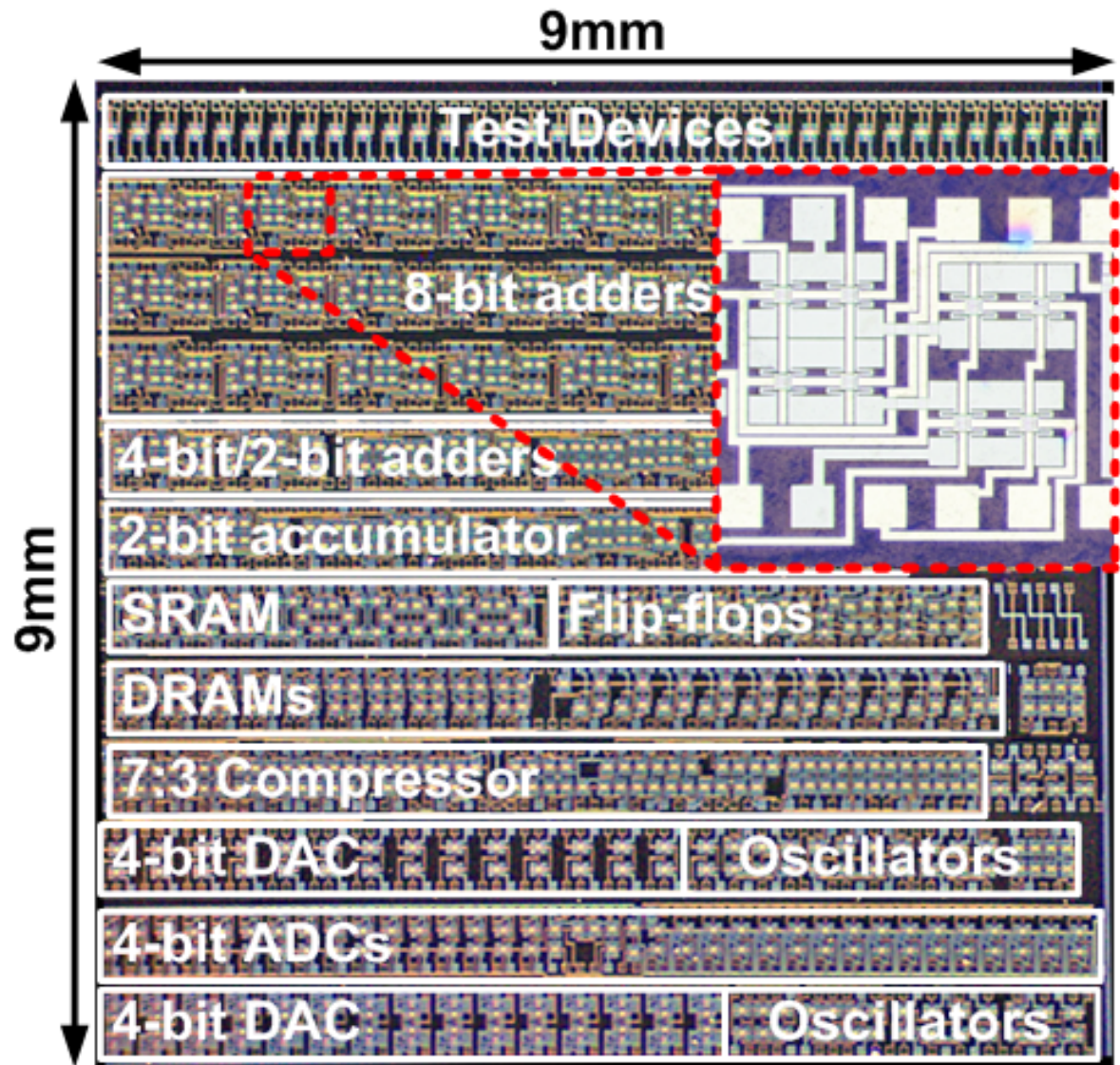


- ❑ Increase contact resistance to improve reliability
 - Delay dominated by mechanics anyways
- ❑ Measured > 60 billion cycles so far

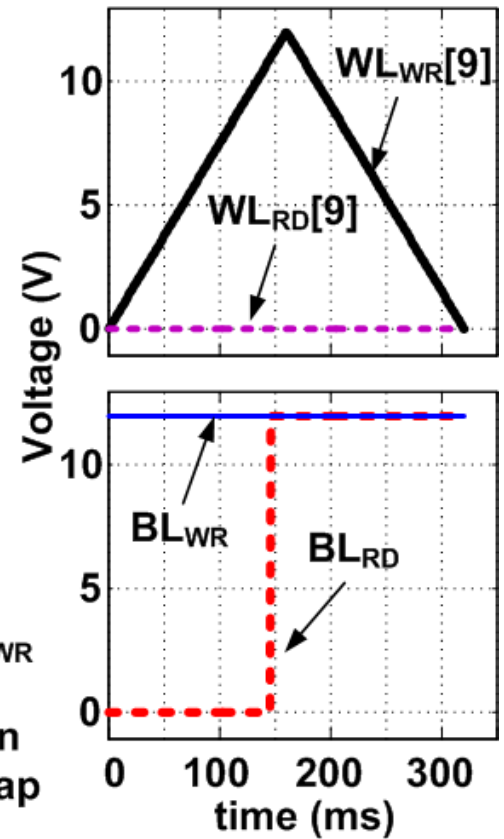
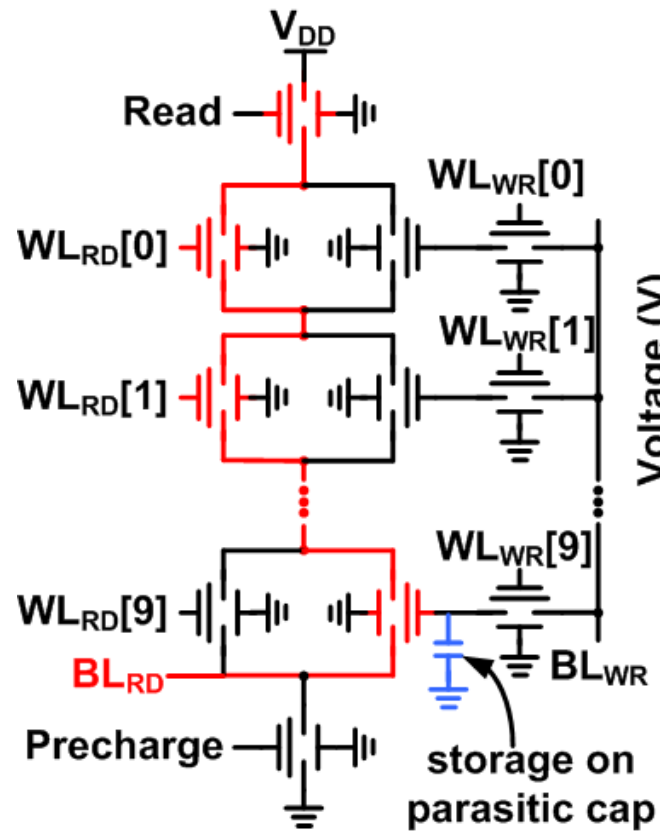
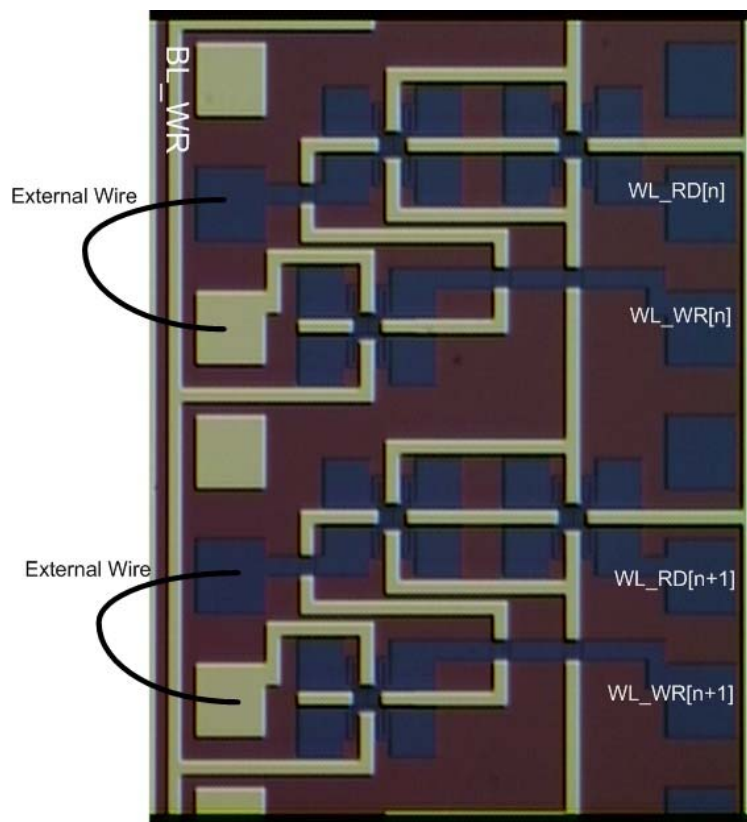


Circuit Demonstration Test-Chip

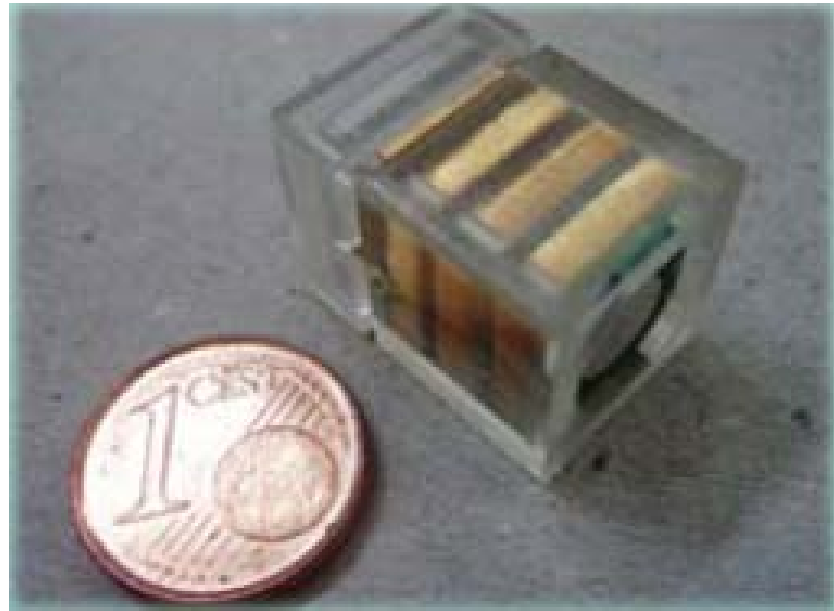
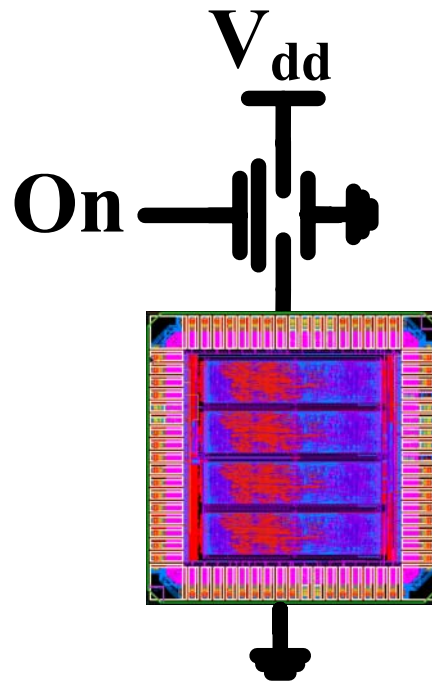
- ❑ Test devices
- ❑ Logic
- ❑ Timing Elements
- ❑ Memory
- ❑ I/O



Relay DRAM



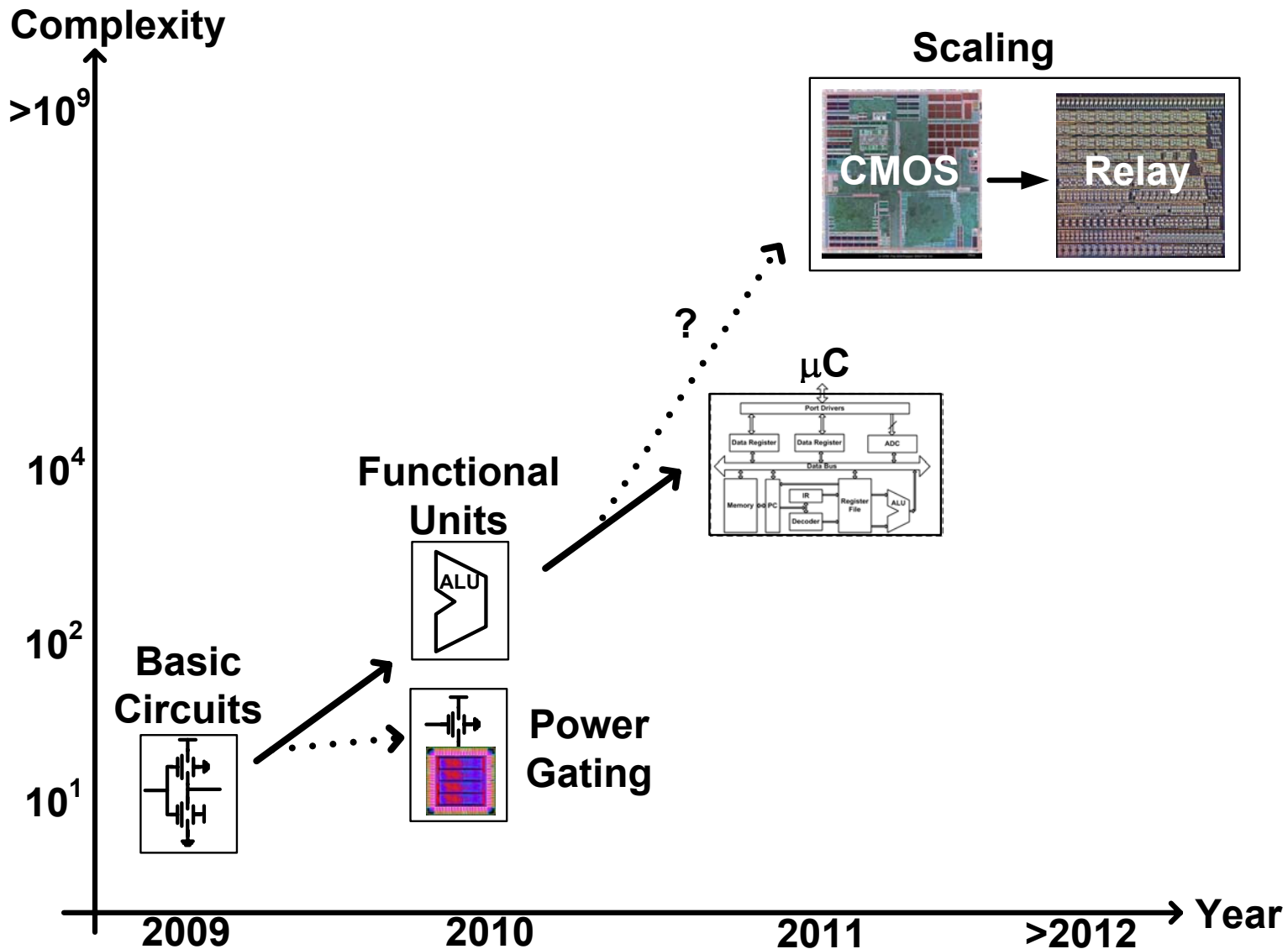
Near-Term Driver: Power Gating



[Picocube, Rabaey]

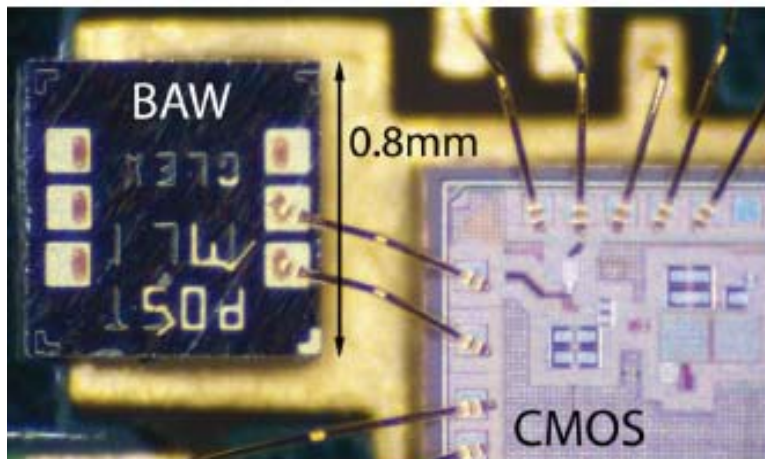
- ❑ Leakage of inactive CMOS circuits often limits embedded devices' lifetime
- ❑ Relay power gates could eliminate leakage

Roadmap: Back to the Future?

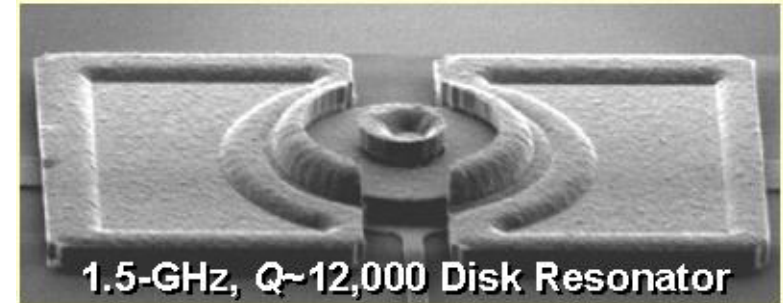


Final Note: Rethinking Scaling

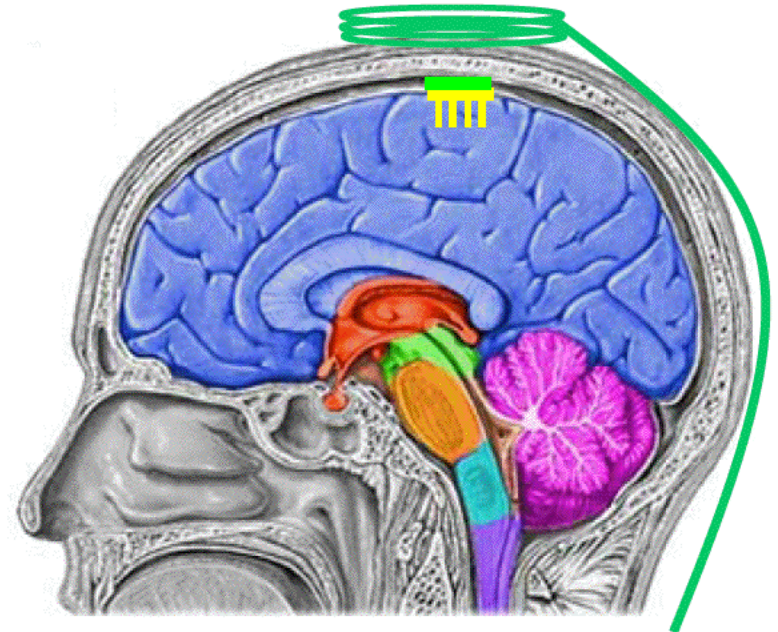
- ❑ Many exciting new apps based on mobility and sensing
- ❑ Innovation and cost driven by functionality – not just computing...



[Rabaey, UCB]



[Nguyen, UCB]



[Venkatraman, Carmena, UCB]